

# **SOLID FADC test status and plan**

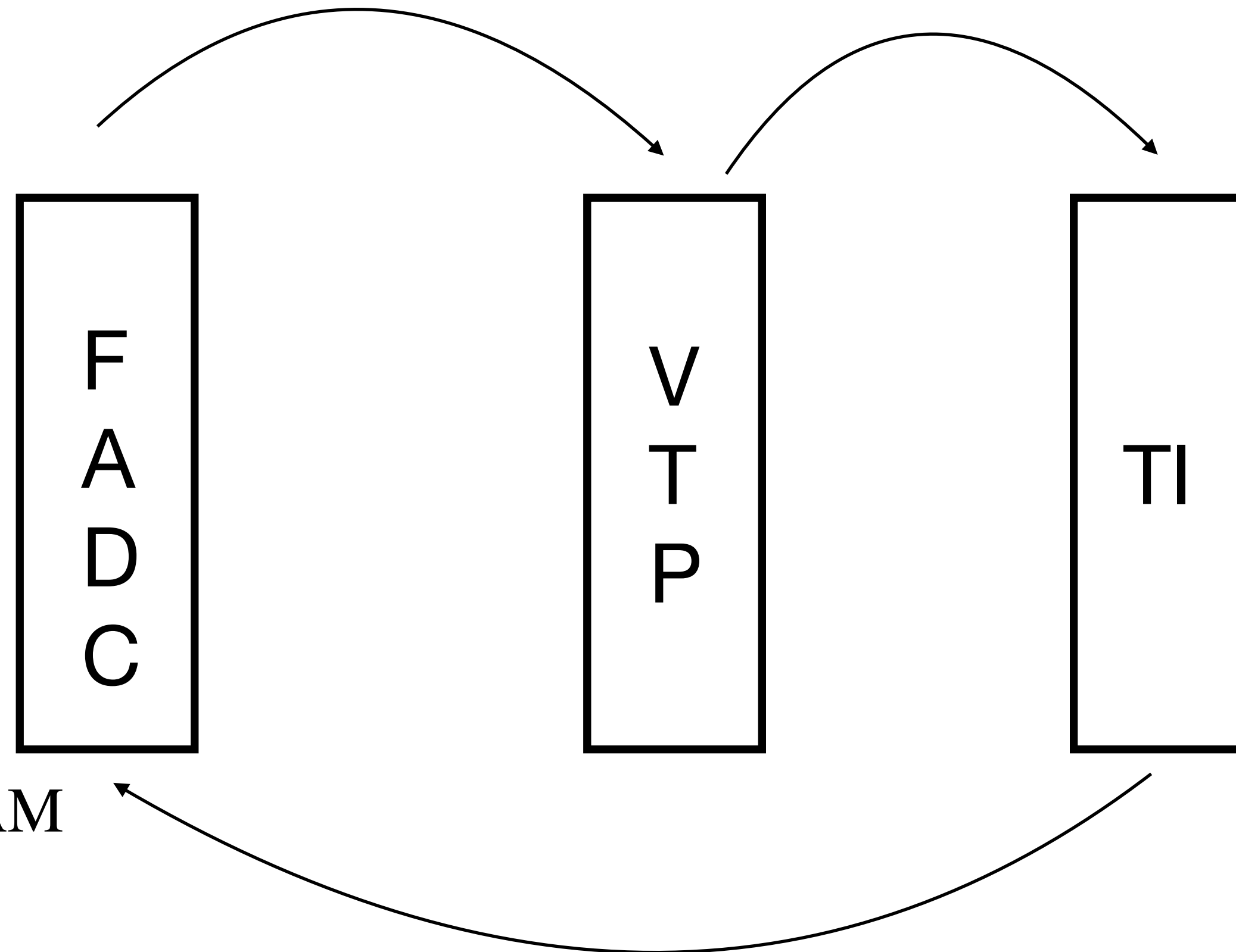
**Hanjie Liu 11/18/2020**

# Test stand setup

compton firmware: generate trigger when there is a signal in FADC channel 0

Trigger\_1: send a trigger to TI to read out FADC data

playback:  
save simulated pulses in RAM  
(32 samples per channel)



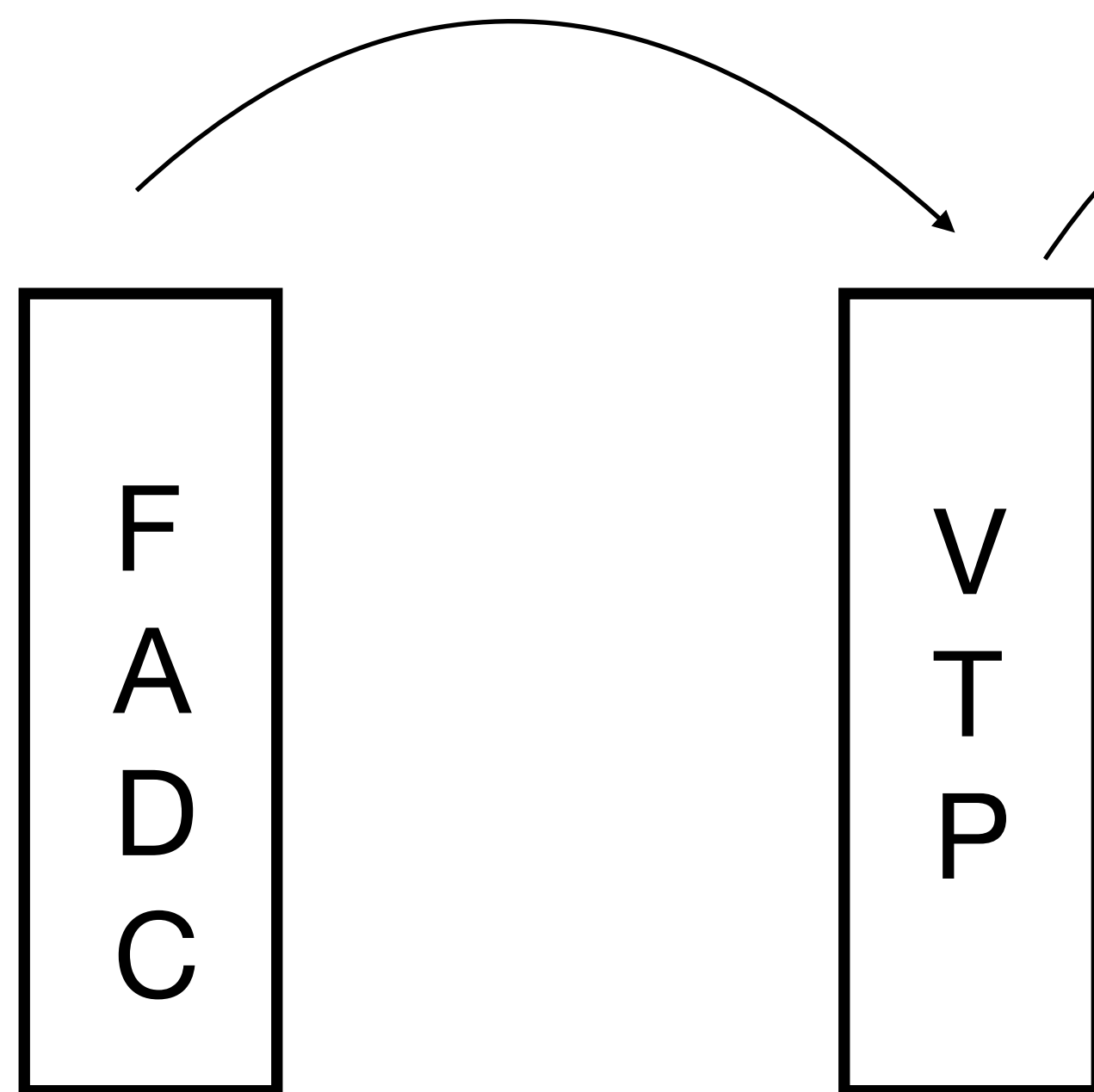
Trigger\_2: TI internal pulser generates a Trigger\_2 type trigger which injects the simulated data in the FADC

(Event rate can be controlled here)

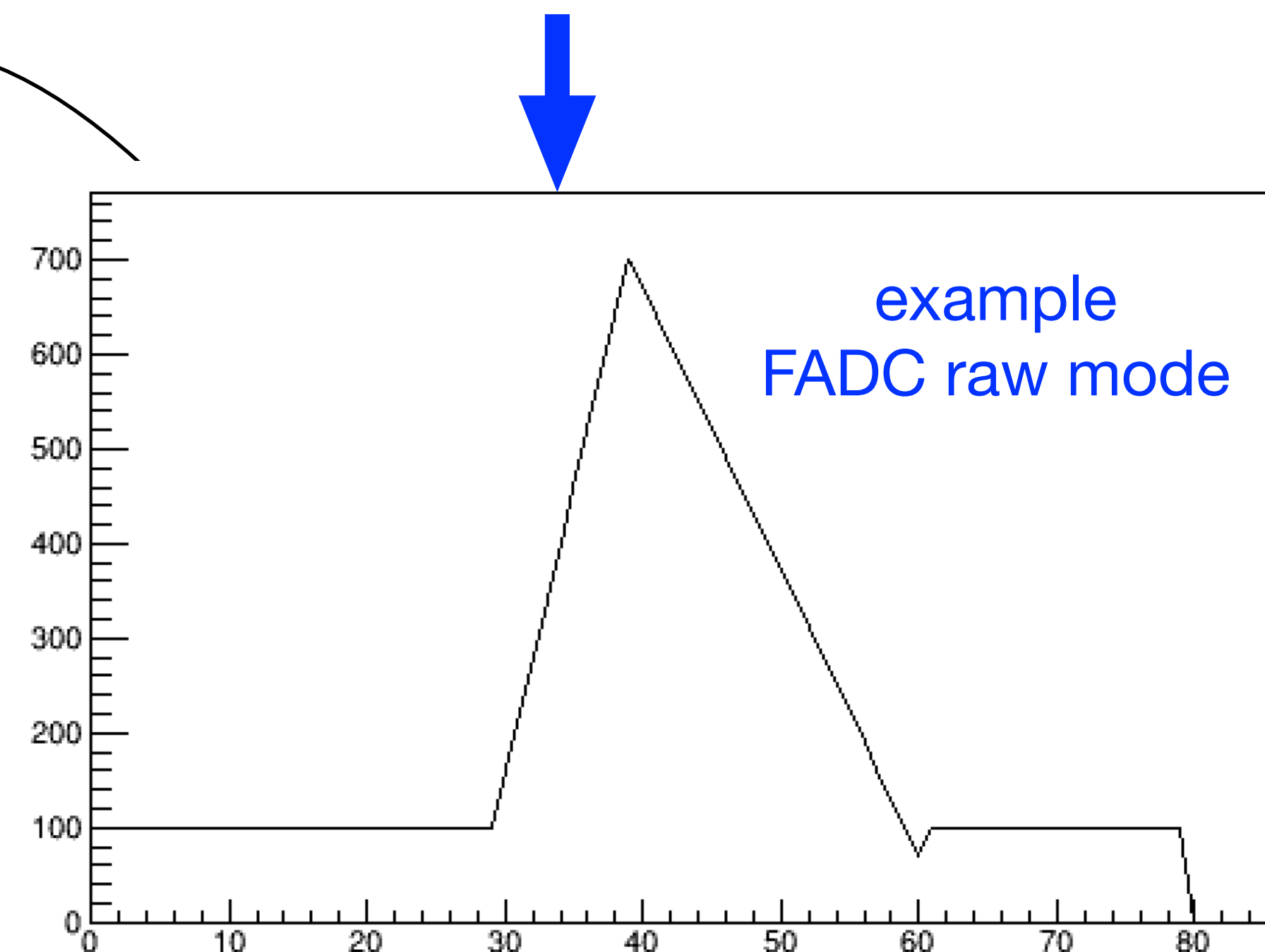
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Trigger\_2: TI internal pulser generates a Trigger\_2 type trigger which injects the simulated data in the FADC

(Event rate can be controlled here;  
rate =  $500\text{kHz}/2^n$ ,  $n=0-15$ )

## FADC dead time measurement plan

- Ben is going to update the FADC firmware to allow part of the FADC channels can accept analog input
- Send MPS signals from the helicity board to FADC so the scalers in VTP can be enabled
- With 16 FADC channels enabled, set the random pulser rate ( $500\text{kHz}/2^n$ ) to:
  - $n=8$ , rate = 1.95 kHz
  - $n=6$ , rate = 7.81 kHz
  - $n=5$ , rate = 15.625 kHz
  - $n=4$ , rate = 31.25 kHz
  - $n=3$ , rate = 62.5 kHz
  - $n=2$ , rate = 125 kHz
  - $n=1$ , rate = 250 kHz
- Measure the FADC dead time as  $(1 - \text{FADC\_counts}/\text{scaler\_counts})$